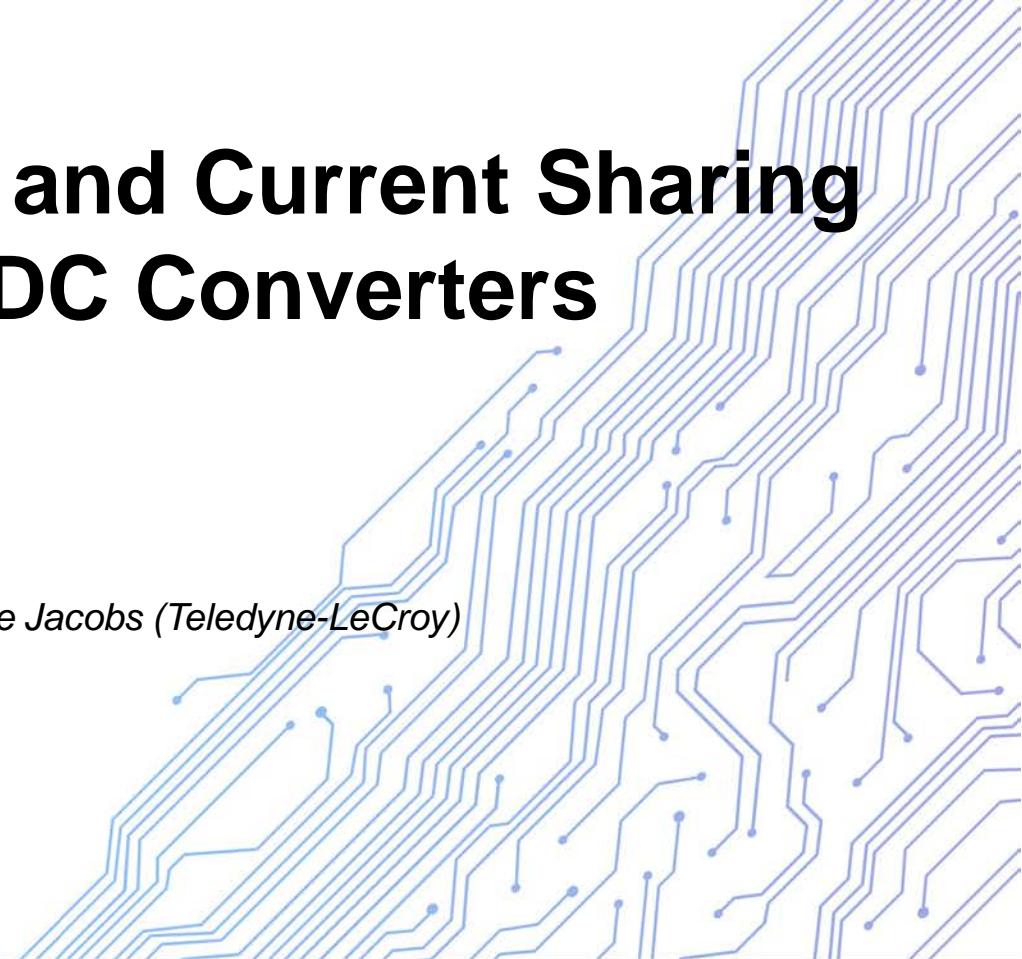


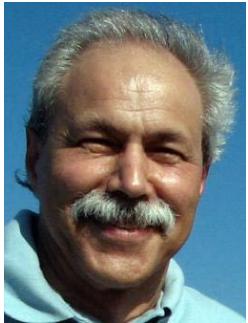
Measuring Current and Current Sharing in Multi-Phase DC-DC Converters

Istvan Novak, (Oracle Corporation)

Peter J. Pupalaikis (Teledyne-LeCroy), Lawrence Jacobs (Teledyne-LeCroy)



SPEAKER



Istvan Novak

Senior Principal Engineer, Oracle Corporation

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Istvan is a Senior Principle Engineer at Oracle. Besides signal integrity design of high-speed serial and parallel buses, he has been engaged in the design and characterization of power-distribution networks and packages for mid-range servers. He creates simulation models, and develops measurement techniques for power distribution. Istvan has twenty plus years of experience with high-speed digital, RF, and analog circuit and system design. He is a Fellow of IEEE for his contributions to signal-integrity and RF measurement and simulation methodologies and has twenty five patents in the areas of power distribution design and precision measurements.



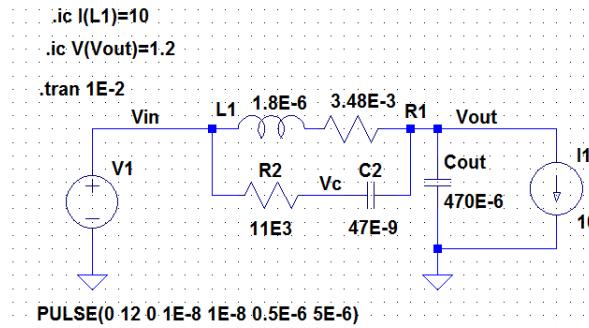
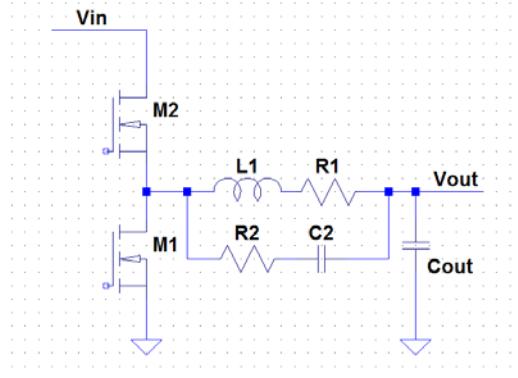
Introduction

Why measure current:

- Protection
- Overcurrent limit
- Undercurrent limit
- Efficiency and load monitoring

How to measure current:

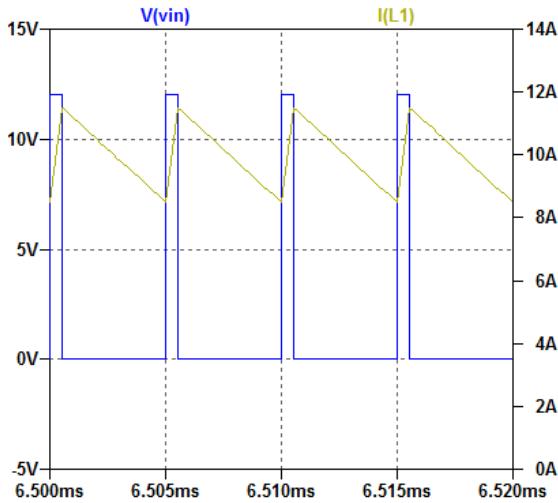
- Shunt resistor
- Current clamp
- Magnetic sensor
- RC across inductor



RC Across Inductor

Switch-node voltage and current:

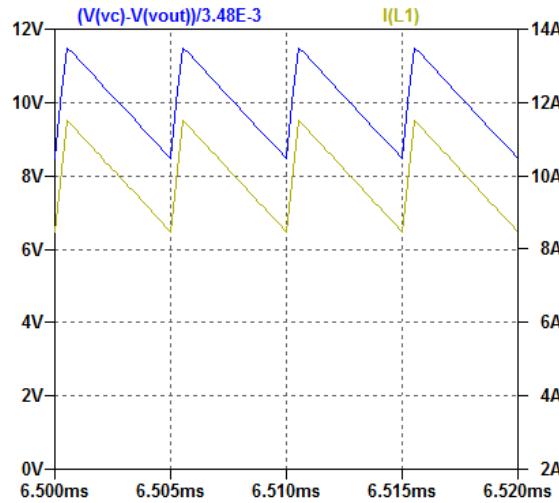
- 12V input, 1.2V output
- Loss-less waveforms



Compare waveforms:

- 10A DC load
- 1.8uH 3.48mOhm inductor
- 11kOhm / 47nF RC

$$\tau = 517 \text{ us}$$



RC Across Inductor Time Constant Range

	R2 [Ohm]	C2 [F]	Rs [Ohm]	Approximate.time constant [s]
Probe-tip 1	17.8k	5.6n	10	100u
Probe-tip 2	8.45k	47n	1.18	400u
Probe-tip 3	16k	47n	0	800u
Probe-tip 4	34k	47n	1.18	1600u



High current, low voltage, high loss

Low current, high voltage, low loss

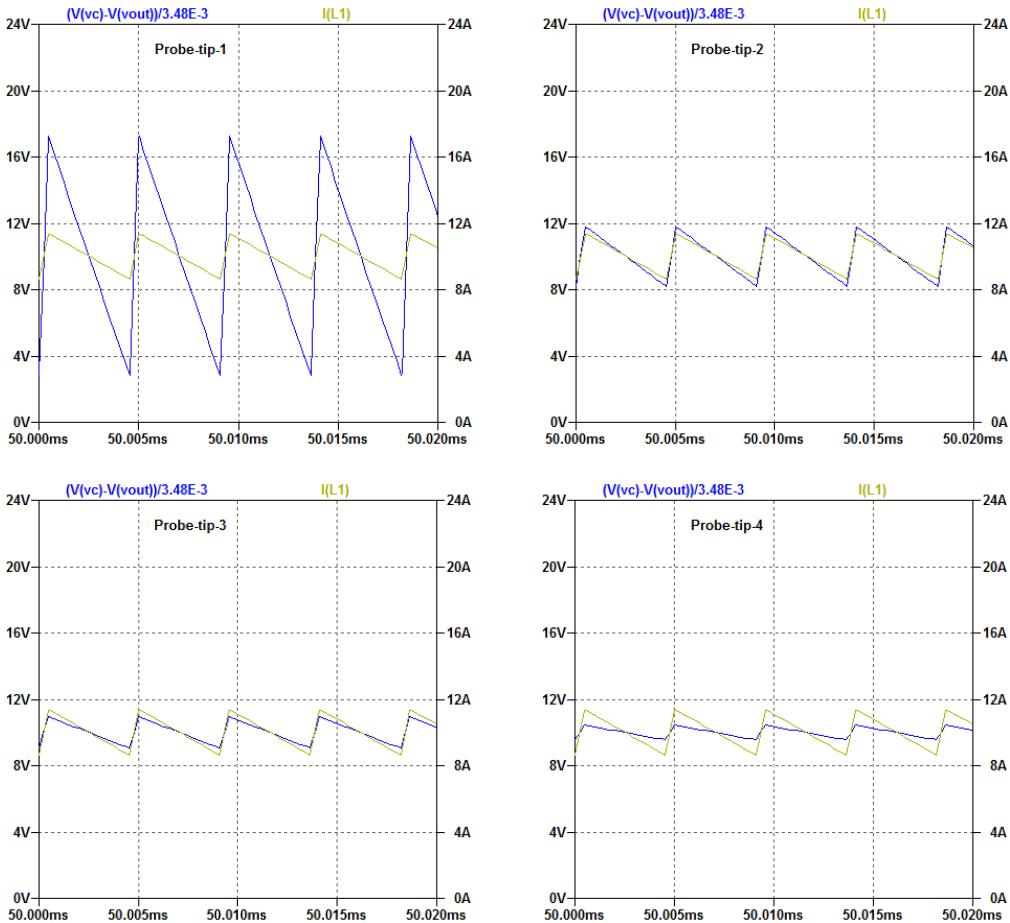


RC Across Inductor Time Constant Mismatch

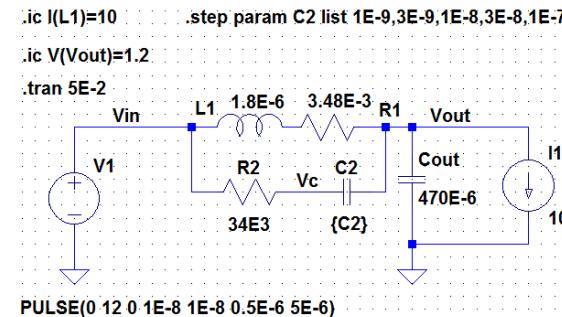
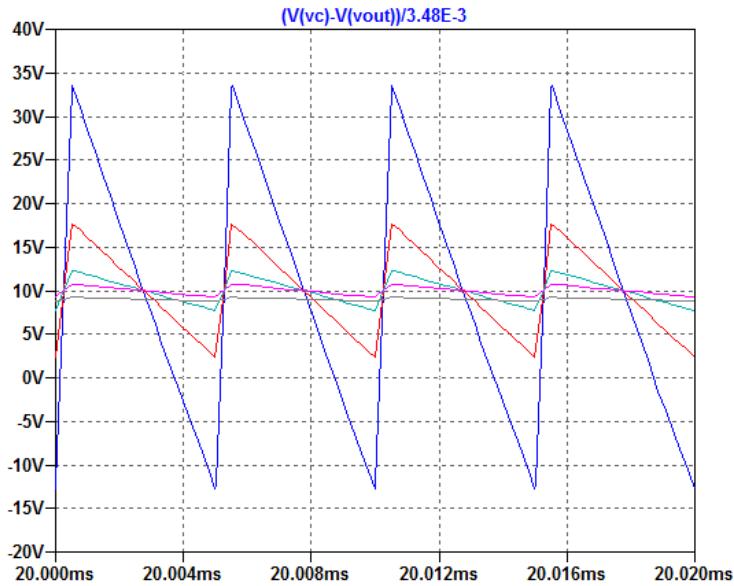
Same DUT (10A DC)
Four different RC networks

- DC average is the same
- AC swing varies

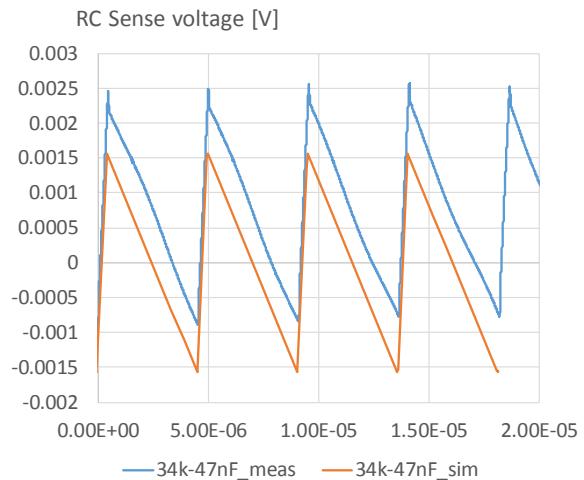
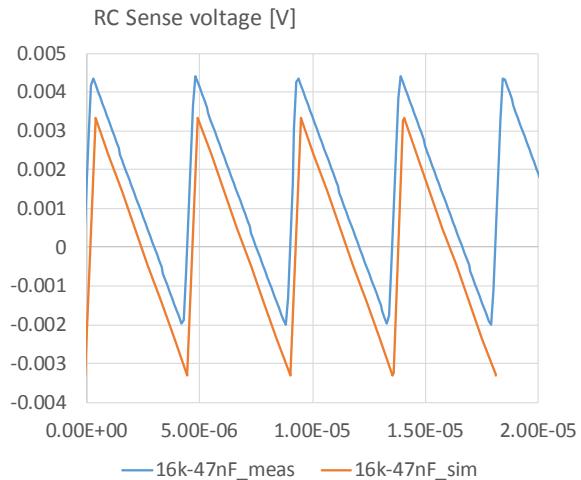
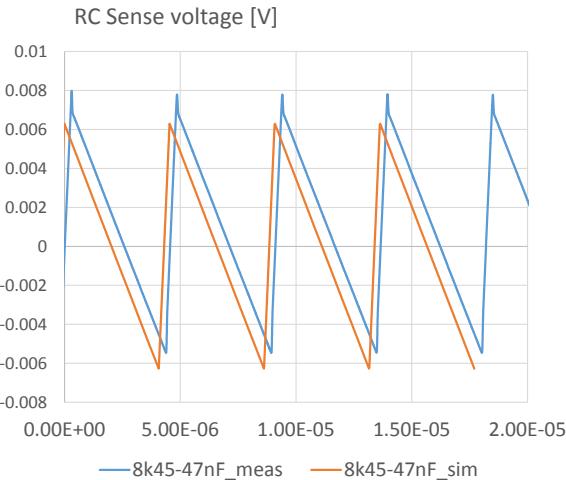
	R2 [Ohm]	C2 [F]
Probe-tip 1	17.8k	5.6n
Probe-tip 2	8.45k	47n
Probe-tip 3	16k	47n
Probe-tip 4	34k	47n



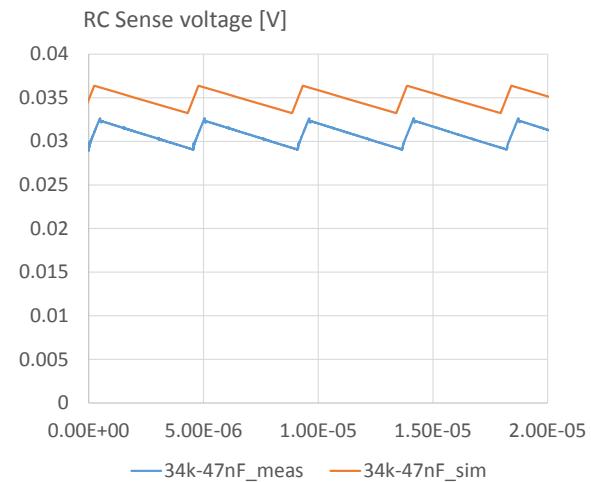
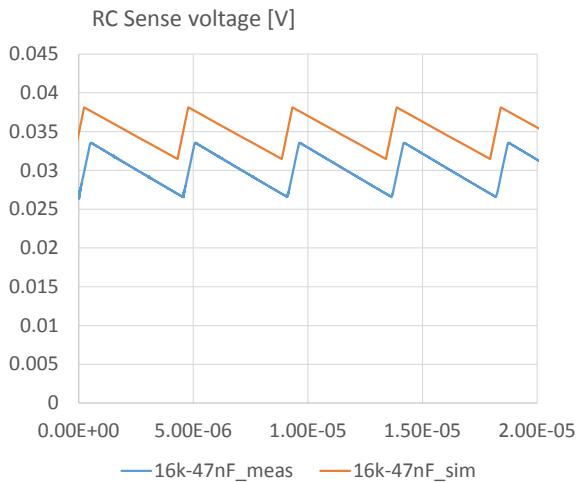
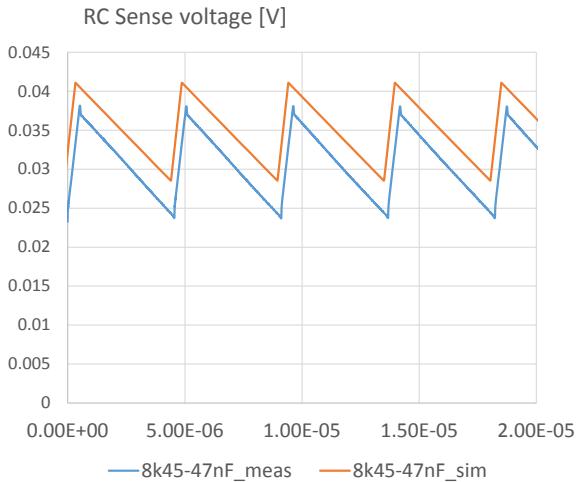
RC Across Inductor: Varying C



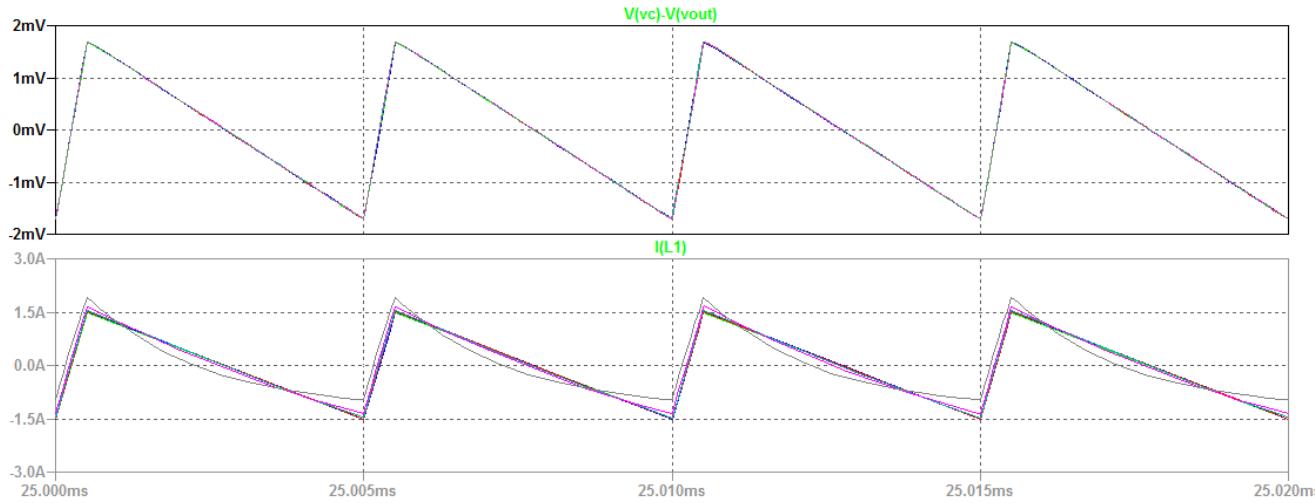
RC Across Inductor Sense Voltage Correlation, 0A DC Load



RC Across Inductor Sense Voltage Correlation, 10A DC Load



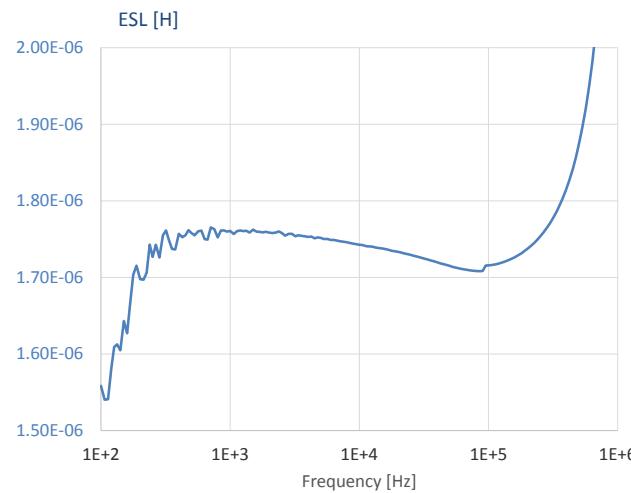
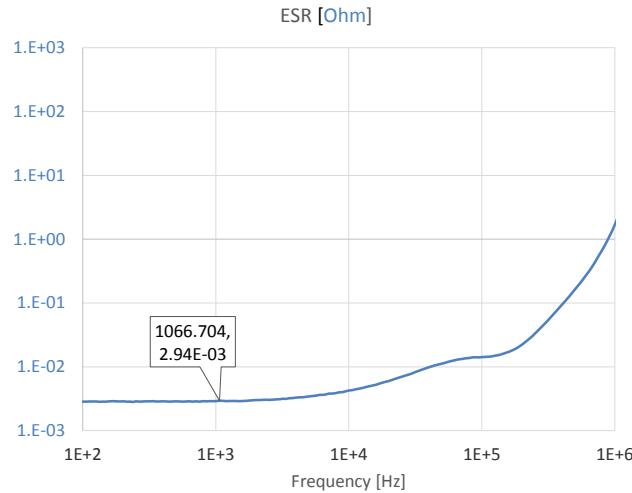
RC Across Inductor Varying Inductor Loss



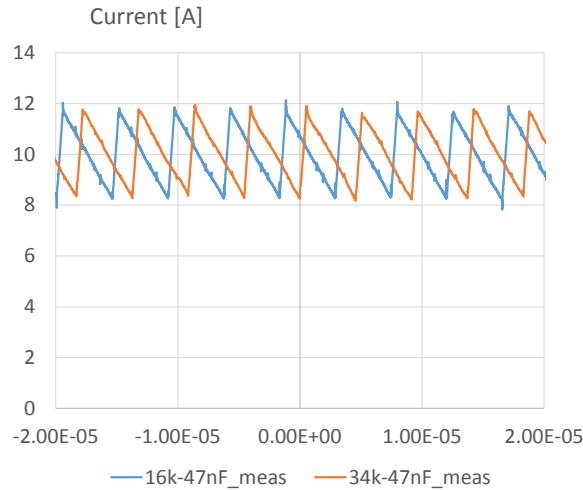
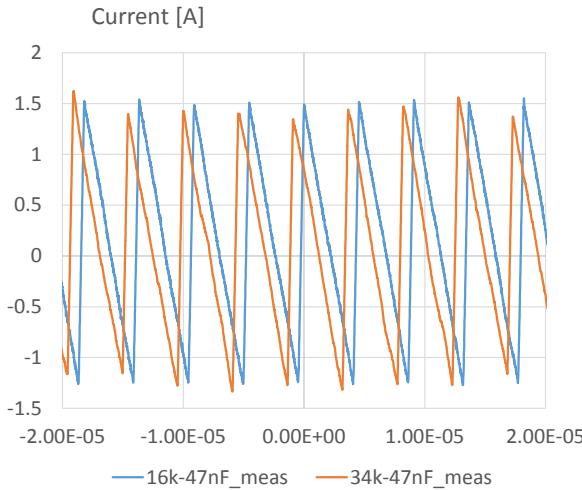
Rdc:
3 mOhm
10 mOhm
30 mOhm
0.1 ohm
0.3 Ohm
1 Ohm



RC Across Inductor Measured Inductor Parameters



RC Across Inductor Correlation



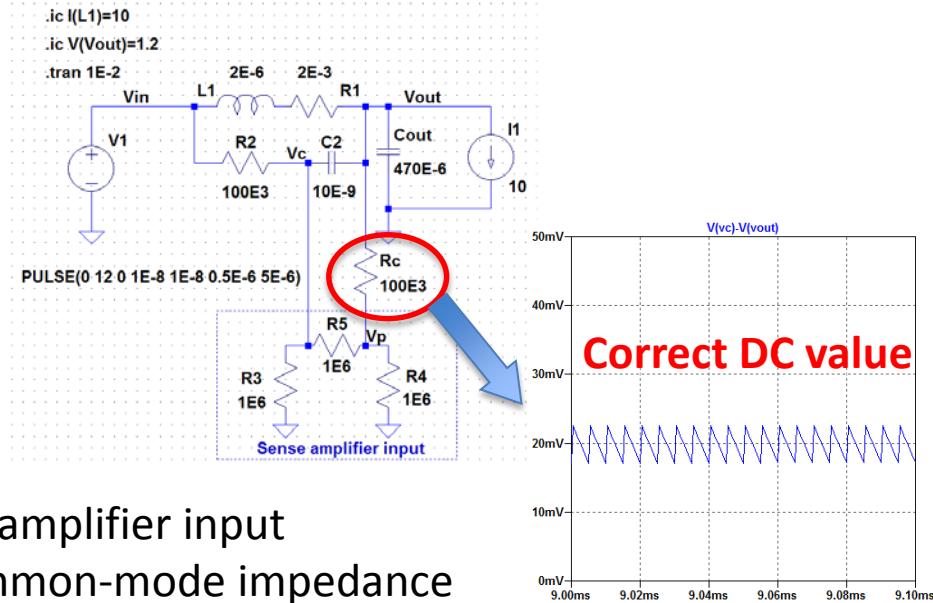
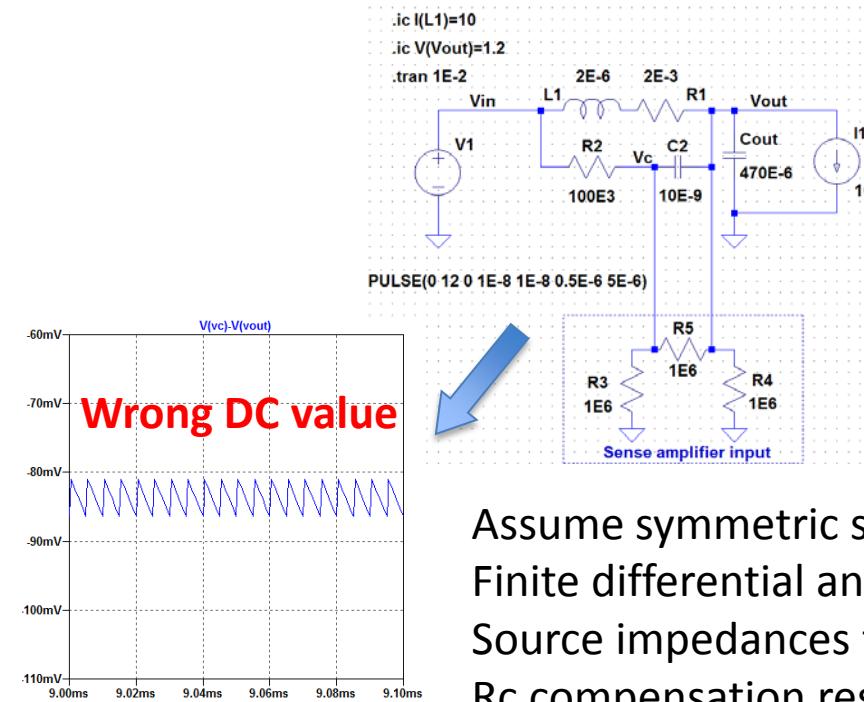
Same DUT
Two different RC probe tips

- Left plot: 0A DC load
- Right plot: 10A DC load

Note: different scales



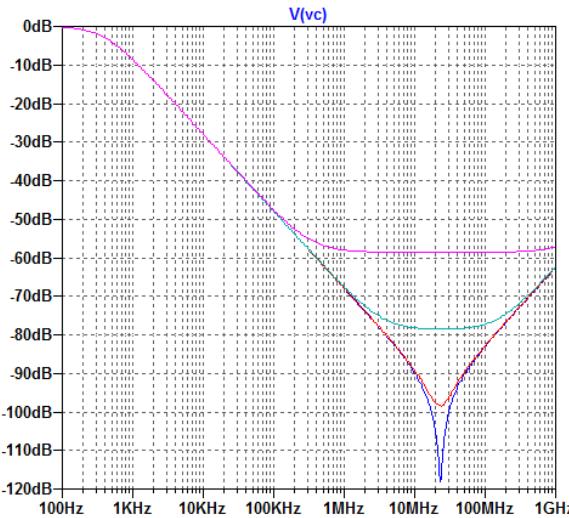
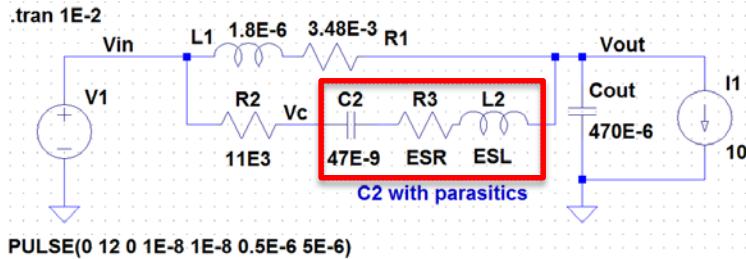
RC Across Inductor: Probe Loading



Assume symmetric sense amplifier input
Finite differential and common-mode impedance
Source impedances to the two input terminals are different
Rc compensation resistor balances the source impedance



RC Across Inductor: Capacitor Parasitics

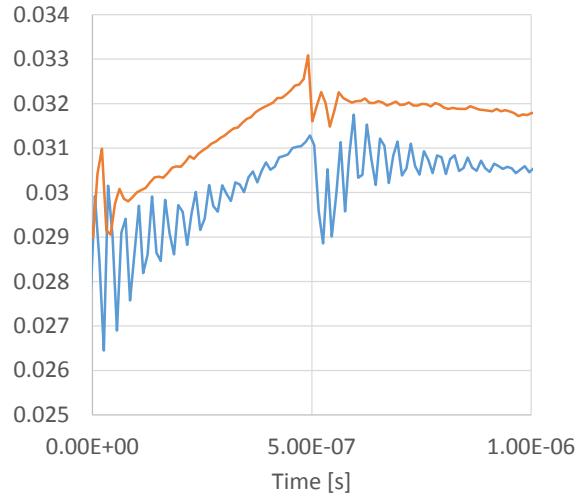


1 nH ESL
ESR stepped through:
10 mOhm
100 mOhm
1 Ohm
10 Ohm



RC Across Inductor: Noise Pickup

Current-sense voltage across C2



Noise can be picked up:

- in connecting wires
- in RC probe tip

Ferrite absorbers can reduce noise



Impedance Measurement Noise Floor

$$B = \frac{\sqrt{2}}{I \cdot \sqrt{M} \cdot \sqrt{K}} \sqrt{\left[VDIV_V \cdot 10^{-\frac{SNR_{Vn}}{10}} + \left(\frac{Z}{R_s} \right)^2 \cdot VDIV_I \cdot 10^{-\frac{SNR_{In}}{10}} \right] \cdot (-\ln(1 - F))}$$

- B is the bounds on the error, in Ω such that for a measured impedance \hat{Z} :

$$|\hat{Z} - |Z| \cdot e^{j \cdot \theta_Z}| < B$$

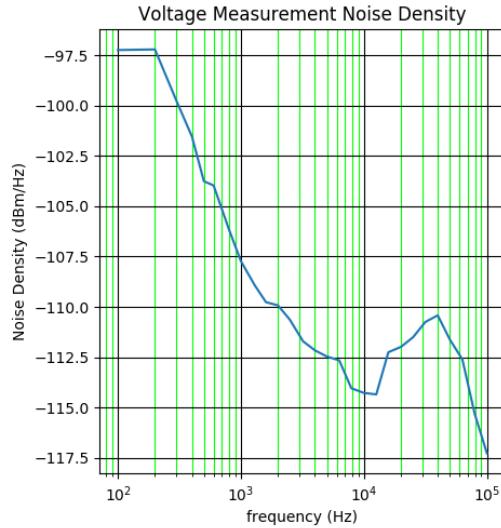
with a certainty of F/100%.

- Z is the actual impedance being measured
- R_s is the resistance of the sense resistor used to measure the transient current by inferring the current by a voltage measurement across the resistor.
- $VDIV_V$ and $VDIV_I$ are the volt/division settings of the oscilloscope channels measuring the voltage and the voltage across the current sense resistor, respectively.
- SNR_V and SNR_I are the normalized signal-to-noise ratios of the oscilloscope channels measuring the voltage and the voltage across the current sense resistor, respectively.
- M is the number of averaged measurements.
- K is the number of points in the acquisition
- I is the amount of transient current injected used to stimulate a voltage transient, and thus an impedance.



Impedance Measurement Noise Floor

Typical Noise Statistics on Impedance Measurements. Voltage Measurement Noise Density at 20mV/div (on the left) and Voltage Measurement Normalized SNR at 20mV/div (on the right).



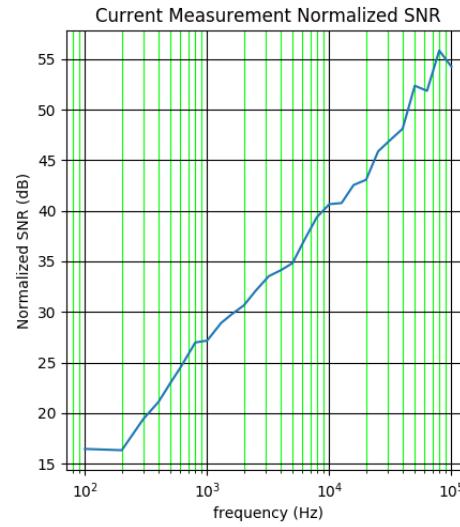
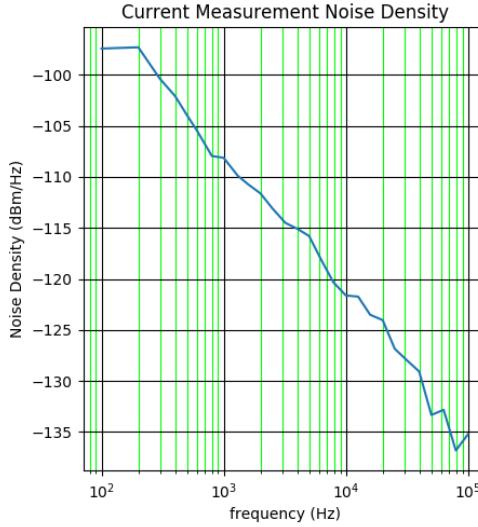
Zero-impedance noise floor:

$$\lim_{Z \rightarrow 0} B = \frac{\sqrt{2} \cdot VDIV_V \cdot 10^{-\frac{SNR_{V_n}}{10}}}{I \cdot \sqrt{M} \cdot \sqrt{K}} \cdot \sqrt{-\ln(1 - F)}$$



Impedance Measurement Noise Floor

Typical Noise Statistics on Impedance Measurements. Current Measurement Noise Density at 50mV/div (on the left) and Current Measurement Normalized SNR at 50mV/div (on the right).

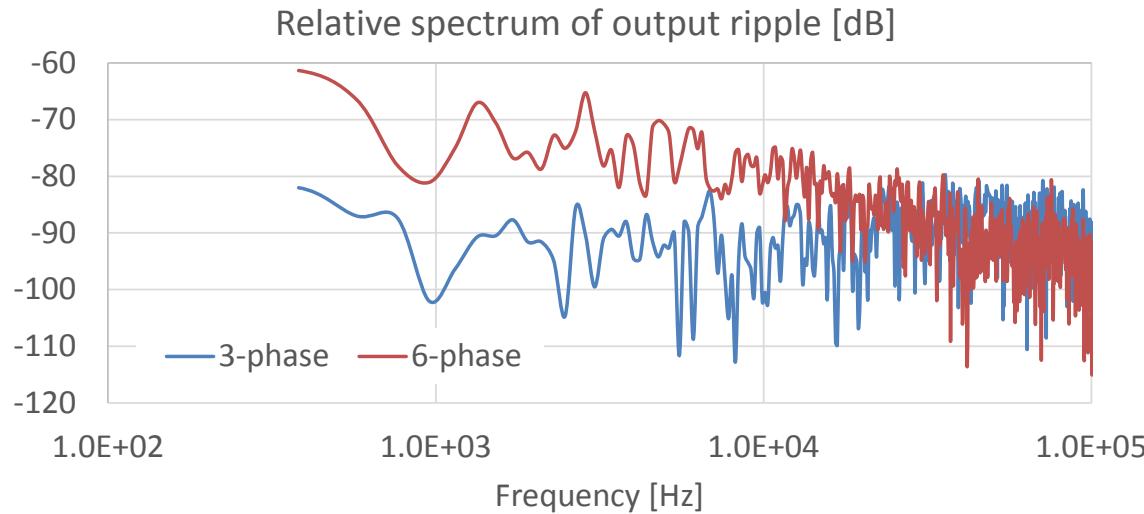


Zero-impedance noise floor:

$$\lim_{Z \rightarrow 0} B = \frac{\sqrt{2} \cdot VDIV_V^2 \cdot 10^{-\frac{SNR_{V_n}}{10}}}{I \cdot \sqrt{M} \cdot \sqrt{K}} \cdot \sqrt{-\ln(1-F)}$$



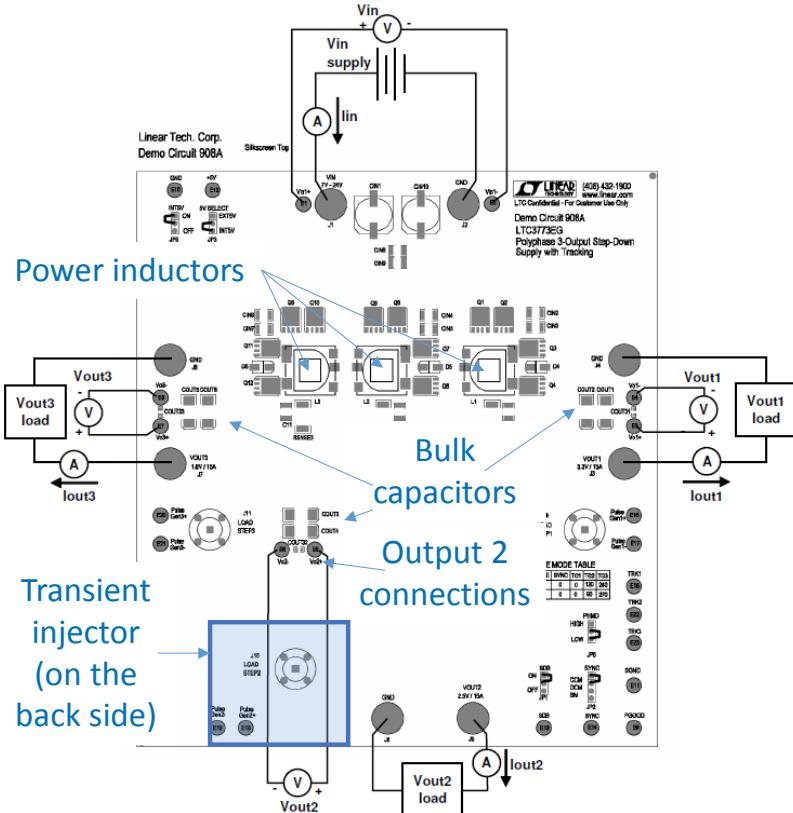
Low-Frequency DUT Noise



Low-frequency spectral density of output ripple for a three-phase and a six-phase DUT.

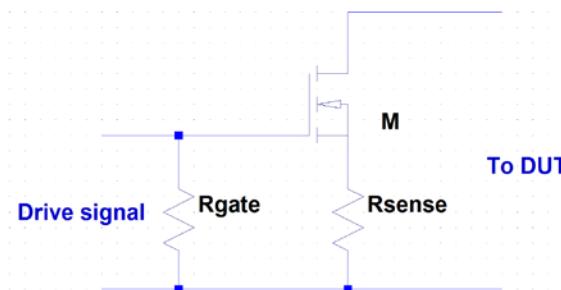


Three-Phase DUT: Outline



Top view of a three-phase evaluation board.

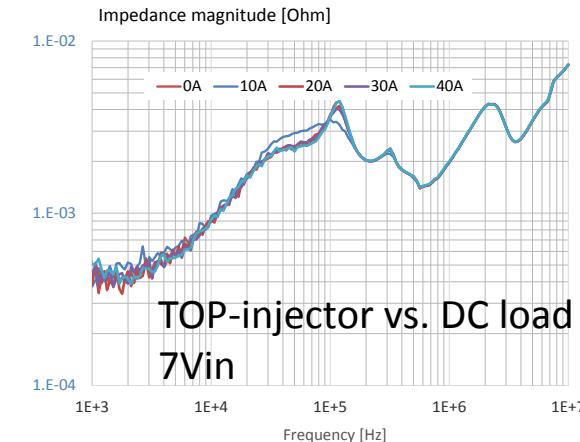
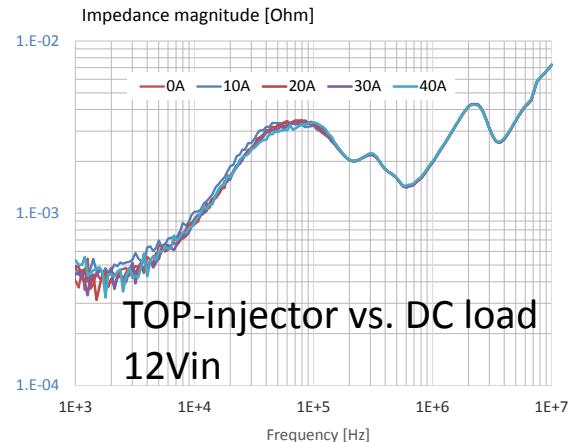
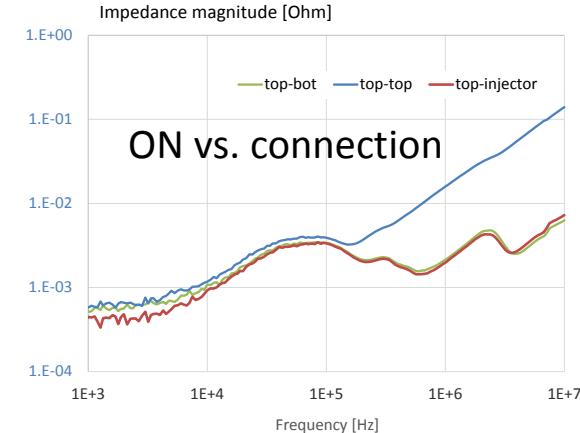
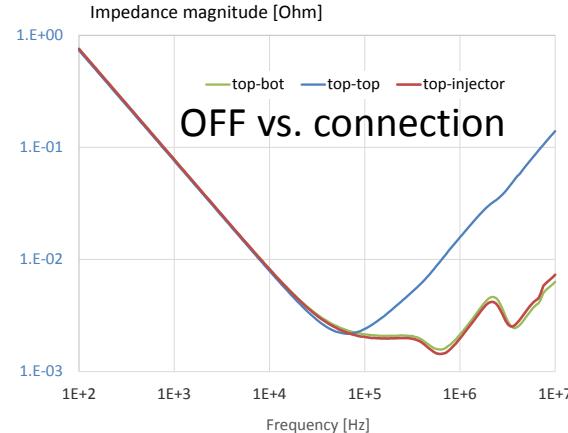
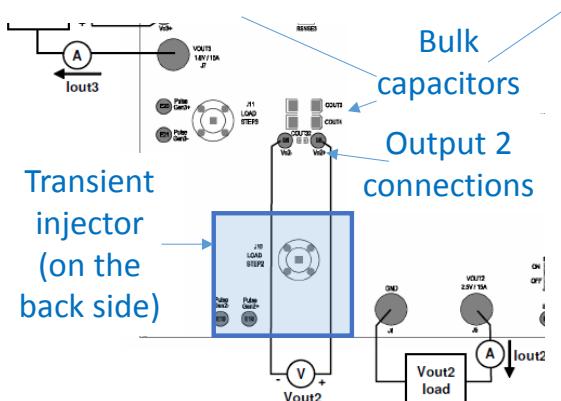
- Three independent outputs: combined
- Current-mode control
- 12V input
- 1.2V output
- 3x15A maximum current
- Transient injector at each output



Three-Phase DUT

Small-signal Zout

10 dBm VNA source power
Three connection options

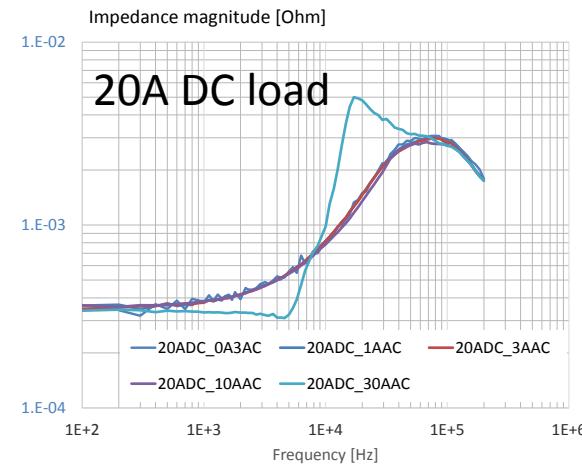
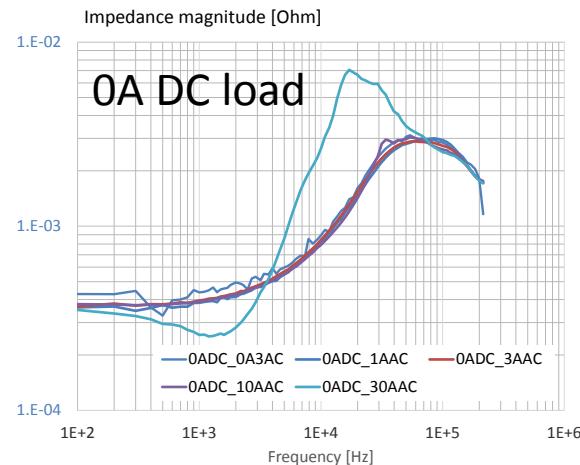
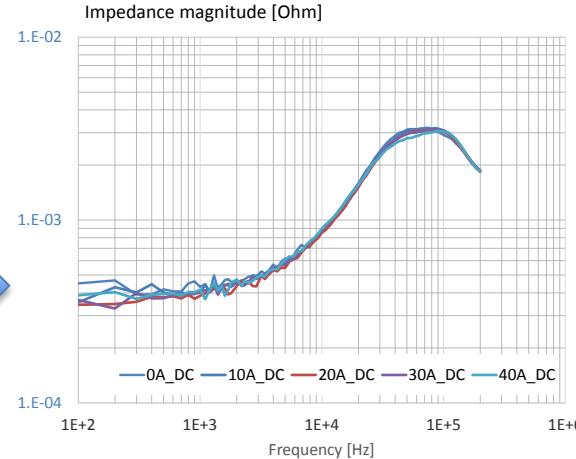


Three-Phase DUT

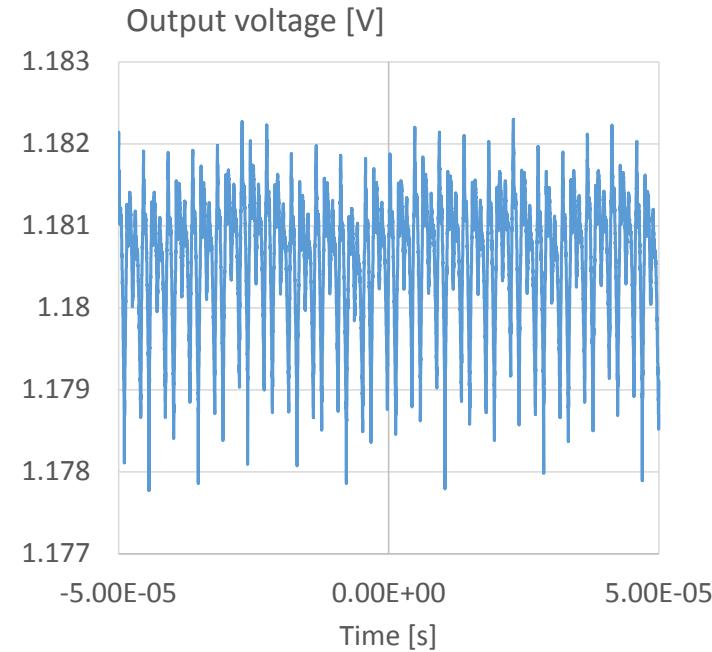
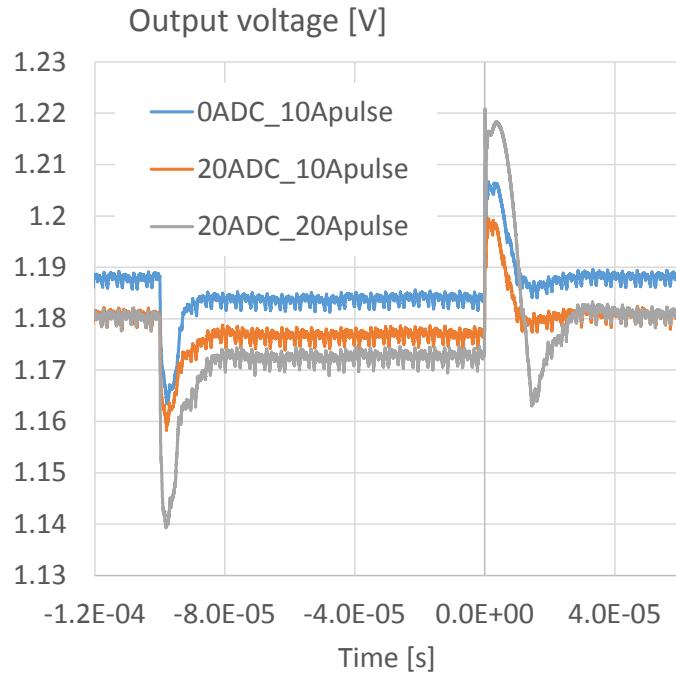
Large-signal Zout

Output impedance vs.
AC test current with
0A and 20A DC load.
AC pulse current:
0.3App
1App
3App
10App
30App

Output impedance vs.
DC load current with
1App test current

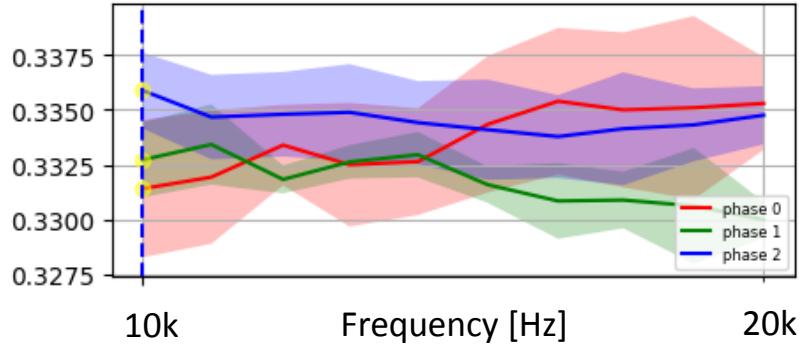


Three-Phase DUT: Transient Response

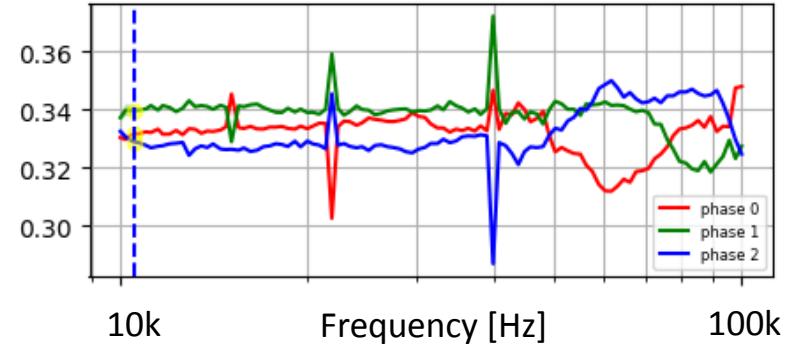


Three-Phase DUT: Current Sharing

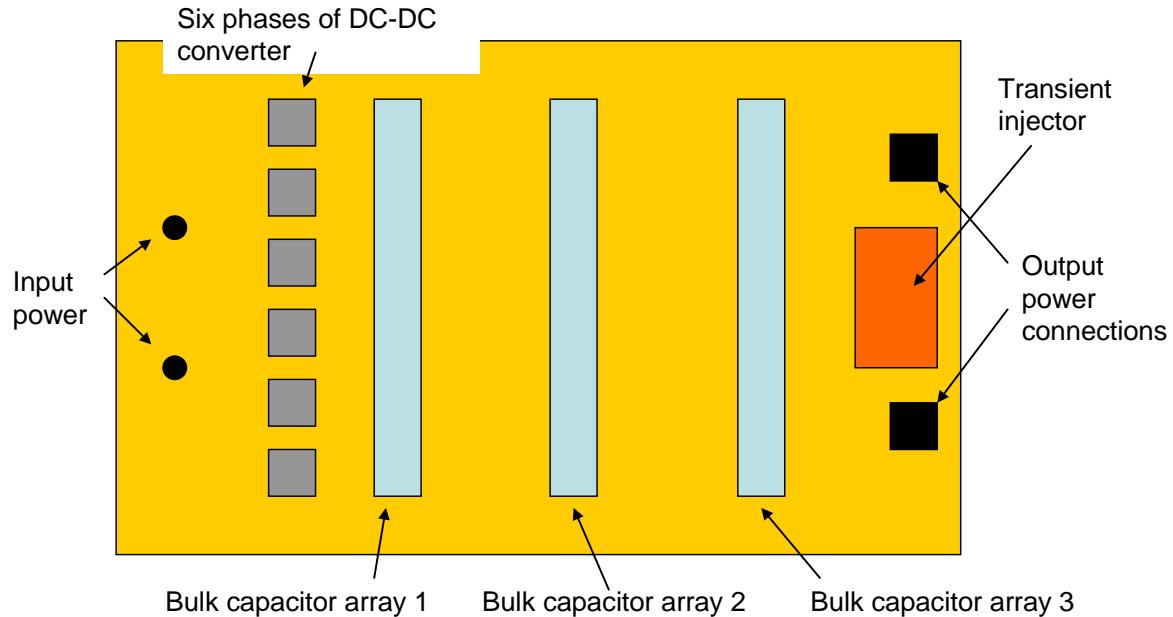
current sharing magnitude



current sharing magnitude



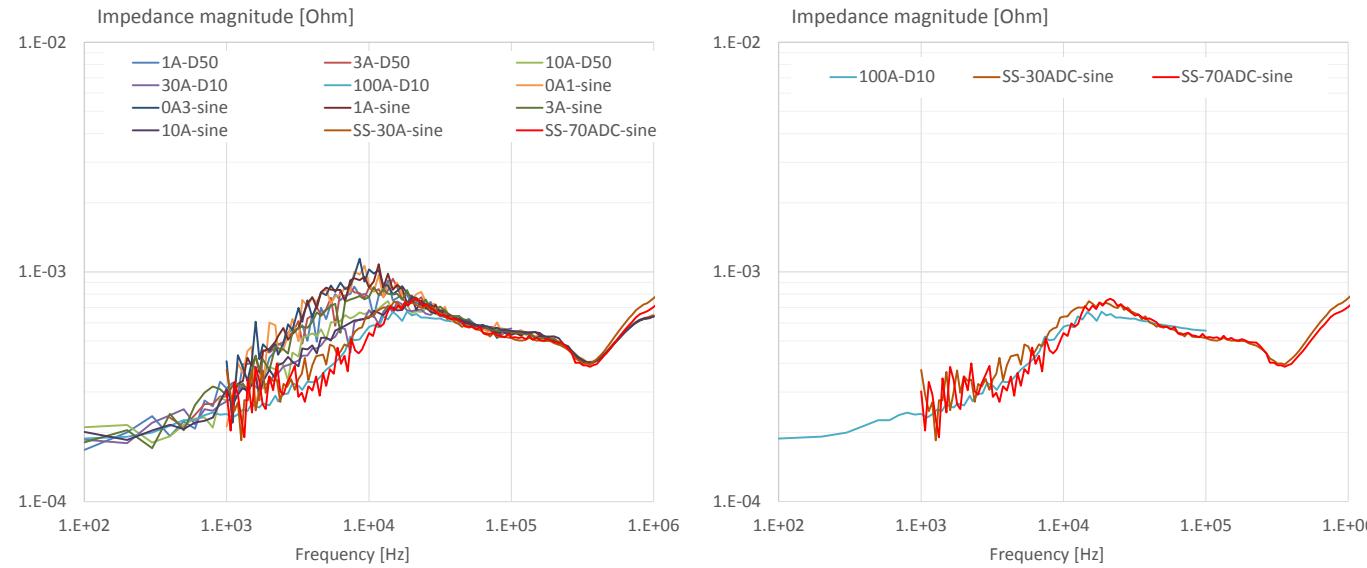
Six-Phase DUT: Outline



- 12V input
- 1.05V output
- Digital control
- 200+A max current



Six-Phase DUT: Output Impedance



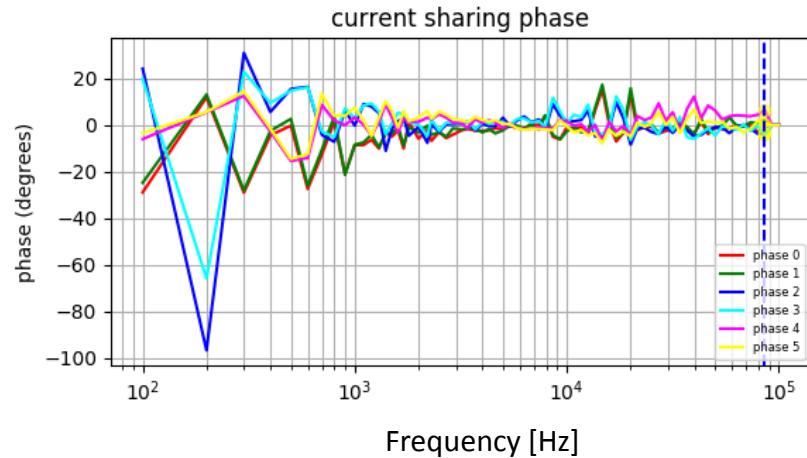
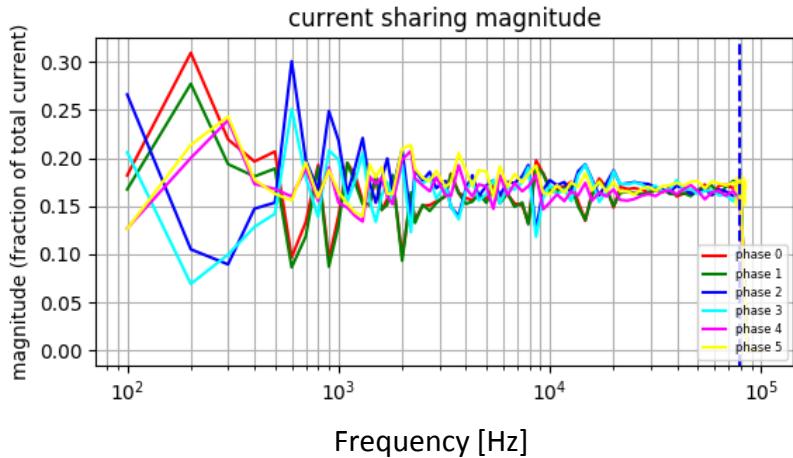
Various test conditions:

- Small-signal VNA
- Small-medium-large signal AC
- Small-medium-large signal pulse

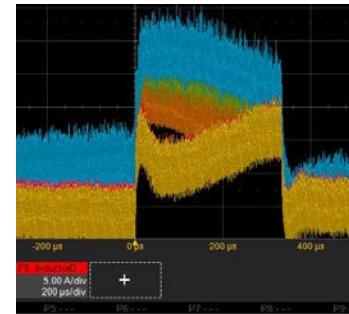
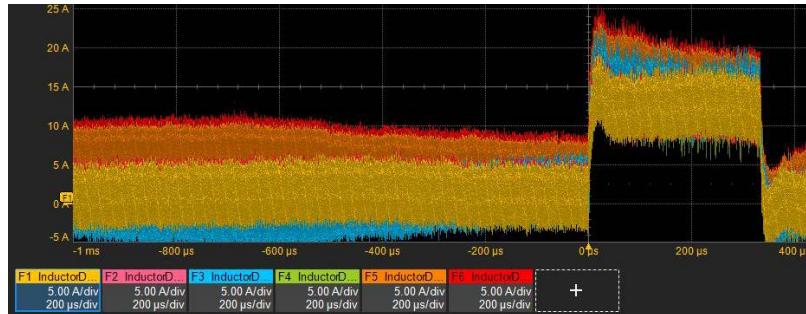
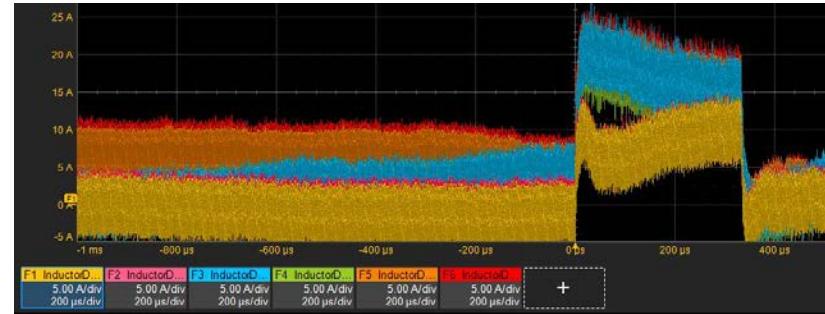
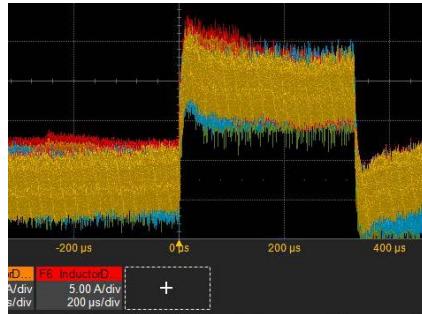


Six-Phase DUT

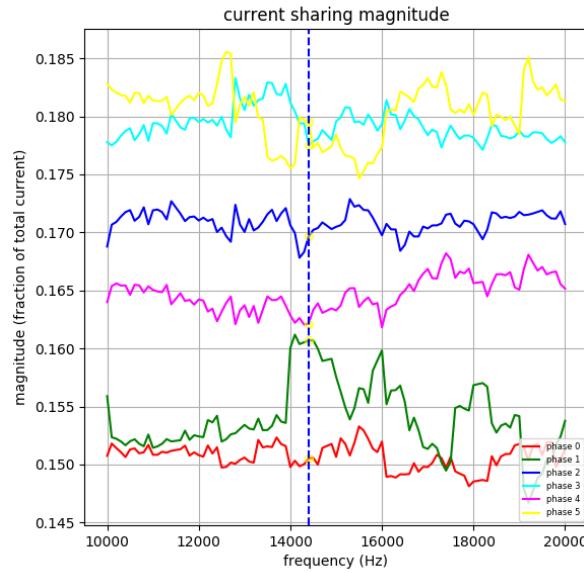
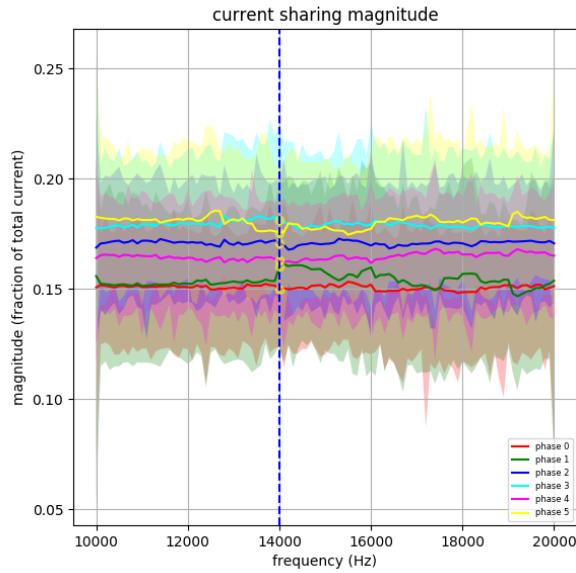
Current Sharing, Frequency Domain



Six-Phase DUT: Current Sharing, Time Domain



Production Board: Current Sharing



- Controlled system activity
- Six-phase converter
- Monitoring mode



Conclusions

- Time constant mismatch of RC sense circuit can be compensated for in DSP engine
- Few steps of fixed RC time constants cover full practical range
- Finite probe input impedance requires balancing of source impedance
- Resistor in series to RC capacitor can help suppress high-frequency noise
- Small-signal, large-signal, frequency domain and time-domain results agree within the bounds of linearity as long as connections are the same
- Monitoring mode can test current sharing vs. frequency of live DUTs



Thank you!

QUESTIONS?

